

RELIABILITY MONITOR

| PRODUCT | MONITOR DATE | DATE CODE | ASSEMBLY FACILITY | ASSEMBLY LOT NO | PROCESS TYPE | PACKAGE TYPE |
|---------|--------------|-----------|-------------------|-----------------|-------------------|--------------|
| DS1669 | Aug-97 | 9701 B3 | OMEDATA | DD642763AAC1 | 1.2μ OX/NI EEPROM | 08 SOIC 208 |

STRESS/JOB NO.

READPOINT (Sample Size/No. of Fails)

Preconditioning (P/C):
HTC Vapor Phase
P-20239

| | |
|-------------------|--------------|
| <u>Electrical</u> | <u>Cum %</u> |
| 234/0 | 0.0% |

Infant / High Voltage Life **
125°C, 7.0 V.
P-20483, P-20599

| | | | |
|--------------|---------------|-------------|----------------------|
| <u>48 Hr</u> | <u>336 Hr</u> | <u>1KHr</u> | <u>*Failure Rate</u> |
| 230/0 | 76/0 | 76/0 | 31 Fits |

*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 eV; Voltage Derating B = 1.0

** with Write Cycle Program stress = 60-/hr/cell

Temp Cycle
-55°C to +125°C
P-20600

| | | |
|--------------|-------------|--------------|
| <u>300 ~</u> | <u>1K ~</u> | <u>Cum %</u> |
| 38/0 | 38/0 | 0.0% |

Biased Moisture
85°C/85% RH, 5.5 V.
P-20601

| | | |
|---------------|---------------|--------------|
| <u>274 Hr</u> | <u>959 Hr</u> | <u>Cum %</u> |
| 75/0 | 75/0 | 0.0% |

Storage Life
150°C, No bias
P-20602

| | | | |
|-------------|---------------|-------------|--------------|
| <u>0 Hr</u> | <u>336 Hr</u> | <u>1KHr</u> | <u>Cum %</u> |
| 38/0 | 38/0 | 38/0 | 0.0% |

Write Data

Failure Mode

Failure Analysis